

Workshop on sapphire detector construction

Thursday, 11 January 2024

Characterization and qualification of sapphire sensors with X-rays: Characterization and qualification of sapphire sensors with X-rays (10:45 - 11:45)

time	[id] title	presenter
10:45	[8] Measurements in Tomsk	Dr TYAZHEV, Anton
10:55	[9] Measurements in Padova	VASIUKOV, Sergii VASIUKOV, Sergii
11:05	[10] Diamond measurements under irradiation and measurement of CCE and mu-tau	Dr TRUCCHI, Daniele
11:25	[11] Discussion: exploitation of X-rays for future sapphire characterization, possibility of disentangling and mitigating non-ohmic contact effects	ALL